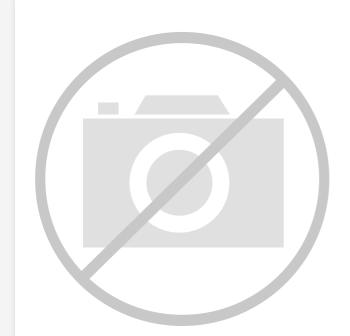
E. Semiconductor Corporation - ISPLSI 2096A-80LQN128 Datasheet



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Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	24
Number of Macrocells	96
Number of Gates	4000
Number of I/O	96
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	128-BQFP
Supplier Device Package	128-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/isplsi-2096a-80lqn128

Email: info@E-XFL.COM

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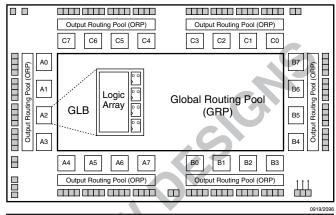
ispLSI° 2096/A

In-System Programmable High Density PLD

Features

- ENHANCEMENTS
 - ispLSI 2096A is Fully Form and Function Compatible to the ispLSI 2096, with Identical Timing Specifications and Packaging
- ispLSI 2096A is Built on an Advanced 0.35 Micron E²CMOS[®] Technology
- HIGH DENSITY PROGRAMMABLE LOGIC
- 4000 PLD Gates
- 96 I/O Pins, Six Dedicated Inputs
- 96 Registers
- High Speed Global Interconnect
- Wide Input Gating for Fast Counters, State Machines, Address Decoders, etc.
- Small Logic Block Size for Random Logic
- HIGH PERFORMANCE E²CMOS[®] TECHNOLOGY
- fmax = 125 MHz Maximum Operating Frequency
- tpd = 7.5 ns Propagation Delay
- TTL Compatible Inputs and Outputs
- Electrically Erasable and Reprogrammable
- Non-Volatile
- 100% Tested at Time of Manufacture
- Unused Product Term Shutdown Saves Power
- IN-SYSTEM PROGRAMMABLE
- In-System Programmable (ISP[™]) 5V Only
- Increased Manufacturing Yields, Reduced Time-to-Market and Improved Product Quality
- Reprogram Soldered Devices for Faster Prototyping
- OFFERS THE EASE OF USE AND FAST SYSTEM SPEED OF PLDs WITH THE DENSITY AND FLEXIBILITY OF FIELD PROGRAMMABLE GATE ARRAYS
- Complete Programmable Device Can Combine Glue Logic and Structured Designs
- Enhanced Pin Locking Capability
- Three Dedicated Clock Input Pins
- Synchronous and Asynchronous Clocks
- Programmable Output Slew Rate Control to Minimize Switching Noise
- Flexible Pin Placement
- Optimized Global Routing Pool Provides Global Interconnectivity
- Lead-Free Package Options

Functional Block Diagram



Description

The ispLSI 2096 and 2096A are High Density Programmable Logic Devices. The devices contain 96 Registers, 96 Universal I/O pins, six Dedicated Input pins, three Dedicated Clock Input pins, two dedicated Global OE input pins and a Global Routing Pool (GRP). The GRP provides complete interconnectivity between all of these elements. The ispLSI 2096 and 2096A feature 5V insystem programmability and in-system diagnostic capabilities. The ispLSI 2096 and 2096A offer nonvolatile reprogrammability of the logic, as well as the interconnect to provide truly reconfigurable systems.

The basic unit of logic on these devices is the Generic Logic Block (GLB). The GLBs are labeled A0, A1...C7 (Figure 1). There are a total of 24 GLBs in the ispLSI 2096 and 2096A devices. Each GLB is made up of four macrocells. Each GLB has 18 inputs, a programmable AND/OR/Exclusive OR array, and four outputs which can be configured to be either combinatorial or registered. Inputs to the GLB come from the GRP and dedicated inputs. All of the GLB outputs are brought back into the GRP so that they can be connected to the inputs of any GLB on the device.

Select devices have been discontinued. See Ordering Information section for product status

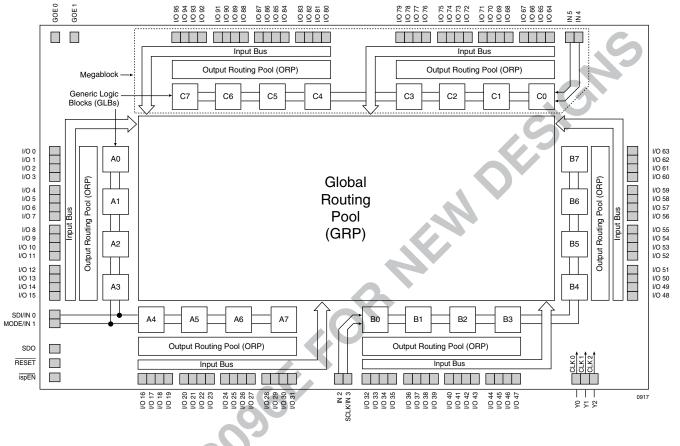
LATTICE SEMICONDUCTOR CORP., 5555 Northeast Moore Ct., Hillsboro, Oregon 97124, U.S.A. Tel. (503) 268-8000; 1-800-LATTICE; FAX (503) 268-8556; http://www.latticesemi.com

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Functional Block Diagram

Figure 1. ispLSI 2096/A Functional Block Diagram



The devices also have 96 I/O cells, each of which is directly connected to an I/O pin. Each I/O cell can be individually programmed to be a combinatorial input, output or bi-directional I/O pin with 3-state control. The signal levels are TTL compatible voltages and the output drivers can source 4 mA or sink 8 mA. Each output can be programmed independently for fast or slow output slew rate to minimize overall output switching noise.

Eight GLBs, 32 I/O cells, two dedicated inputs and two ORPs are connected together to make a Megablock (Figure 1). The outputs of the eight GLBs are connected to a set of 32 universal I/O cells by the two ORPs. Each ispLSI 2096 and 2096A device contains three Megablocks.

The GRP has as its inputs, the outputs from all of the GLBs and all of the inputs from the bi-directional I/O cells. All of these signals are made available to the inputs of the GLBs. Delays through the GRP have been equalized to minimize timing skew.

Clocks in the ispLSI 2096 and 2096A devices are selected using the dedicated clock pins. Three dedicated clock pins (Y0, Y1, Y2) or an asynchronous clock can be selected on a GLB basis. The asynchronous or Product Term clock can be generated in any GLB for its own clock.



Absolute Maximum Ratings ¹

Supply Voltage V _{cc} 0.5 to +7.0V
Input Voltage Applied2.5 to V _{CC} +1.0V
Off-State Output Voltage Applied2.5 to V _{CC} +1.0V
Storage Temperature
Case Temp. with Power Applied55 to 125°C
Max. Junction Temp. (TJ) with Power Applied 150°C

1. Stresses above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

DC Recommended Operating Condition

SYMBOL	PA	PARAMETER						
V	Cupply Voltage	Commercial $T_A = 0^{\circ}C$ to + 70°C	4.75	5.25	V			
V _{CC}	Supply Voltage	Industrial $T_A = -40^{\circ}C \text{ to } + 85^{\circ}C$	4.5	5.5	V			
V _{IL}	Input Low Voltage		0	0.8	V			
V _{IH}	Input High Voltage		2.0	V _{cc} +1	V			

Table 2 - 0005/2096

Capacitance (T_A=25°C, f=1.0 MHz)

SYMBOL	PARAMETER	TYPICAL	UNITS	TEST CONDITIONS							
C ₁	I/O and Dedicated Input Capacitance	8	pf	$V_{CC} = 5.0V, V_{I/O, IN} = 2.0V$							
C ₂	Clock Capacitance	15	pf	$V_{CC} = 5.0V, V_{Y} = 2.0V$							
				Table 2-0006a							

Data Retention Specifications

PARAMETER	MINIMUM	MAXIMUM	UNITS
Data Retention	20	_	Years
Erase/Reprogram Cycles	10000	_	Cycles

Table 2-0008A-isp



Switching Test Conditions

Input Pulse Levels	GND to 3.0V			
Input Rise and Fall Time	-125	≤ 2 ns		
10% to 90%	Others	≤ 3 ns		
Input Timing Reference Levels	1.5V			
Output Timing Reference Levels	1.5V			
Output Load	See Figure 2			
3-state levels are measured 0.5V from	1 ¹	able 2-0003/2096		

3-state levels are measured 0.5V from steady-state active level.

Output Load Conditions (see Figure 2)

	TEST CONDITION	R1	R2	CL
Α		470Ω	390Ω	35pF
в	Active High	8	390Ω	35pF
D	Active Low	470Ω	390Ω	35pF
	Active High to Z at V _{OH} -0.5V	×	390Ω	5pF
С	Active Low to Z at V _{OL} +0.5V	470Ω	390Ω	5pF

Table 2-0004/2096

Figure 2. Test Load +5V R_1 R_2 R_2 CL^* *CL includes Test Fixture and Probe Capacitance. 0213/2096

DC Electrical Characteristics

Over Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITIO	N	MIN.	TYP. ³	MAX.	UNITS
VOL	Output Low Voltage	I _{OL} = 8 mA		Ι	_	0.4	V
V он	Output High Voltage	I _{OH} = -4 mA		2.4	—	-	V
lı∟	Input or I/O Low Leakage Current	$0V \le V_{IN} \le V_{IL}(Max.)$	Ι	-	-10	μA	
Ін	Input or I/O High Leakage Current	$3.5V \le V_{\rm IN} \le V_{\rm CC}$	Ι	—	10	μA	
IL-isp	ispEN Input Low Leakage Current	$0V \le V_{IN} \le V_{IL} (Max.)$	_	-	-150	μA	
IL-PU	I/O Active Pull-Up Current	$0V \le V_{IN} \le V_{IL}$	$0V \le V_{IN} \le V_{IL}$				μA
los ¹	Output Short Circuit Current	$V_{CC} = 5V, V_{OUT} = 0.5V$	-	-	-200	mA	
	Operating Power Supply Current	V _{IL} = 0.0V, V _{IH} = 3.0V	Commercial	Ι	150	295	mA
	operating rewer supply surrent	f ^{CLOCK} = 1 MHz	Industrial	-	150	-	mA

Table 2-0007/2096

1. One output at a time for a maximum duration of one second. V_{OUT} = 0.5V was selected to avoid test problems by tester ground degradation. Characterized but not 100% tested.

2. Measured using six 16-bit counters.

3. Typical values are at V_{CC} = 5V and T_A = 25°C.

 Maximum I_{CC} varies widely with specific device configuration and operating frequency. Refer to the Power Consumption section of this data sheet and the Thermal Management section of the Lattice Semiconductor Data Book or CD-ROM to estimate maximum I_{CC}.



External Timing Parameters

Over Recommended Operating Conditions										
DADAMETED	TEST ⁴	PEOODIPTION1	-125			00	-8	30		
PARAMETER	COND.	# ²		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	UNITS
t pd1	A	1	Data Propagation Delay, 4PT Bypass, ORP Bypass	-	7.5	١	10.0	-	15.0	ns
t pd2	A	2	Data Propagation Delay	-	10.0	I	13.0	-	18.5	ns
f max	A	3	Clock Frequency with Internal Feedback ³	125	-	100	-	81.0	1	MHz
f max (Ext.)	-	4	Clock Frequency with External Feedback $\left(\frac{1}{tsu2 + tco1}\right)$	100	-	77.0	-	57.0	1	MHz
f max (Tog.)	_	5	Clock Frequency, Max. Toggle	125	-	100	_	83.0	I	MHz
t su1	-	6	GLB Reg. Setup Time before Clock, 4 PT Bypass	5.0	-	6.5		9.0	_	ns
t co1	A	7	GLB Reg. Clock to Output Delay, ORP Bypass	-	4.0	1	5.0	-	6.5	ns
t h1	-	8	GLB Reg. Hold Time after Clock, 4 PT Bypass	0.0	-	0.0	-	0.0	-	ns
t su2	-	9	GLB Reg. Setup Time before Clock	6.0		8.0	-	11.0	-	ns
t co2	-	10	GLB Reg. Clock to Output Delay	-	4.5	-	6.0	-	8.0	ns
t h2	-	11	GLB Reg. Hold Time after Clock	0.0	-	0.0	-	0.0	-	ns
t r1	A	12	Ext. Reset Pin to Output Delay	-	10.0	-	13.5	-	17.0	ns
t rw1	-	13	Ext. Reset Pulse Duration	5.0	-	6.5	-	10.0	-	ns
t ptoeen	В	14	Product Term OE, Enable	_	12.0	-	15.0	-	18.0	ns
t ptoedis	С	15	Product Term OE, Disable	-	12.0	-	15.0	-	18.0	ns
t goeen	В	16	Global OE, Enable	-	7.0	1	9.0	_	12.0	ns
t goedis	С	17	Global OE, Disable	-	7.0	I	9.0	-	12.0	ns
t wh	-	18	External Synchronous Clock Pulse Duration, High	4.0	-	5.0	-	6.0	-	ns
twi	-	19	External Synchronous Clock Pulse Duration, Low	4.0	-	5.0	-	6.0	-	ns
. Unless noted	otherwise	e. all	parameters use the GRP, 20 PTXOR path, ORP and	Y0 clo	ck.				Table	2-0030/2096

1. Unless noted otherwise, all parameters use the GRP, 20 PTXOR path, ORP and Y0 clock.

2. Refer to Timing Model in this data sheet for further details.

3. Standard 16-bit counter using GRP feedback.

4. Reference Switching Test Conditions section.

USFISPISI

See Ordering Information section for product status. Select devices have been discontinued.



Internal Timing Parameters¹

Over Recommended Operating Conditions											
	PARAMETER #2 DESCRIPTION -100 -80 UNIT MIN. MAX. MIN.										
PARAMETER	AETER # ² DESCRIPTION					MAX.	MIN.	MAX.	UNITS		
Inputs											
tio	20	Input Buffer Delay	-	0.2	_	0.5	_	1.8	ns		
t din	21	Dedicated Input Delay	-	1.5	_	2.2	-	4.4	ns		
GRP											
t grp	22	GRP Delay	-	1.3	_	1.7	Ð	2.6	ns		
GLB			•			C					
t 4ptbpc	23	4 Product Term Bypass Comb. Path Delay	-	4.5	-	5.8	_	8.1	ns		
t 4ptbpr	24	4 Product Term Bypass Reg. Path Delay	-	5.0		5.8	_	6.8	ns		
t 1ptxor	25	1 Product Term/XOR Path Delay	-	5.7		6.8	_	8.0	ns		
t20ptxor	26	20 Product Term/XOR Path Delay	-	6.0	_	7.3	_	8.8	ns		
txoradj	27	XOR Adjacent Path Delay ³	-	6.5	_	8.0	_	9.8	ns		
tgbp	28	GLB Register Bypass Delay		0.5	_	0.5	_	1.3	ns		
t gsu	29	GLB Register Setup Time before Clock	0.8	_	1.2	_	1.4	_	ns		
t gh	30	GLB Register Hold Time after Clock	3.0	_	4.0	-	6.0	-	ns		
t gco	31	GLB Register Clock to Output Delay	_	0.2	_	0.3	_	0.4	ns		
t gro	32	GLB Register Reset to Output Delay	_	1.1	_	1.3	_	1.6	ns		
t ptre	33	GLB Product Term Reset to Register Delay	-	4.8	_	6.1	_	8.6	ns		
t ptoe	34	GLB Product Term Output Enable to I/O Cell Delay	-	7.3	_	8.6	_	9.0	ns		
t ptck	35	GLB Product Term Clock Delay	3.3	5.6	4.1	7.1	5.6	10.2	ns		
ORP			•			•		•			
t orp	36	ORP Delay	-	0.8	_	1.4	_	2.0	ns		
t orpbp	37	ORP Bypass Delay	_	0.3	_	0.4	_	0.5	ns		
Outputs											
tob	38	Output Buffer Delay	-	1.2	_	1.6	_	2.0	ns		
tsl	39	Output Slew Limited Delay Adder	-	10.0	_	10.0	_	10.0	ns		
toen	40	I/O Cell OE to Output Enabled	_	3.2	_	4.2	_	4.6	ns		
t odis	41	I/O Cell OE to Output Disabled	-	3.2	_	4.2	_	4.6	ns		
tgoe	42		-	3.8	_	4.8	_	7.4	ns		
Clocks											
t gy0	43	Clock Delay, Y0 to Global GLB Clock Line (Ref. Clock)	2.3	2.3	2.7	2.7	3.6	3.6	ns		
t gy1/2	44	Clock Delay, Y1 or Y2 to Global GLB Clock Line	2.3	2.3	2.7	2.7	3.6	3.6	ns		
Global Rese	et										
tgr	45	Global Reset to GLB	-	6.9	_	9.2	_	11.4	ns		

Table 2-0036/2096

1. Internal Timing Parameters are not tested and are for reference only.

2. Refer to Timing Model in this data sheet for further details.

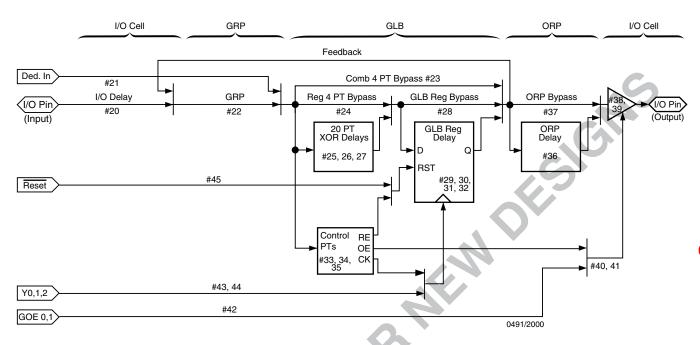
3. The XOR adjacent path can only be used by hard macros.

See Ordering Information section for product status. Select devices have been discontinued.



SF

ispLSI 2096/A Timing Model



Derivations of tsu, th and tco from the Product Term Clock

Note: Calculations are based upon timing specifications for the ispLSI 2096/A-125L.

Table 2-0042B/2096

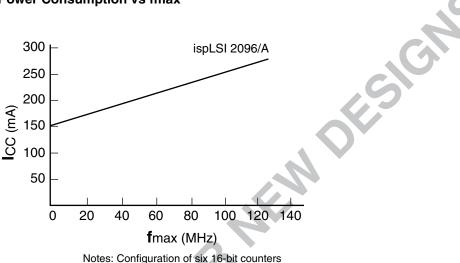


Power Consumption

Power consumption in the ispLSI 2096 and 2096A devices depends on two primary factors: the speed at which the device is operating and the number of Product Terms

used. Figure 4 shows the relationship between power and operating speed.

Figure 4. Typical Device Power Consumption vs fmax



Typical current at 5V, 25°C

ICC can be estimated for the ispLSI 2096/A using the following equation:

ICC(mA) = 20 + (# of PTs * 0.67) + (# of nets * Max freq * 0.011)

Where:

15515

of PTs = Number of Product Terms used in design # of nets = Number of Signals used in device Max freq = Highest Clock Frequency to the device (in MHz)

The I_{CC} estimate is based on typical conditions (V_{CC} = 5.0V, room temperature) and an assumption of two GLB loads on average exists. These values are for estimates only. Since the value of I_{CC} is sensitive to operating conditions and the program in the device, the actual I_{CC} should be verified.

0127/2096



Specifications ispLSI 2096/A

Pin Description

NAME	Р	QFP 8		PIN N	UMBE	RS	DESCRIPTION
$\begin{array}{c} \text{I/O} \ 0 - \text{I/O} \ 5\\ \text{I/O} \ 6 - \text{I/O} \ 11\\ \text{I/O} \ 12 - \text{I/O} \ 17\\ \text{I/O} \ 12 - \text{I/O} \ 23\\ \text{I/O} \ 24 - \text{I/O} \ 29\\ \text{I/O} \ 36 - \text{I/O} \ 29\\ \text{I/O} \ 36 - \text{I/O} \ 41\\ \text{I/O} \ 42 - \text{I/O} \ 47\\ \text{I/O} \ 48 - \text{I/O} \ 53\\ \text{I/O} \ 54 - \text{I/O} \ 59\\ \text{I/O} \ 66 - \text{I/O} \ 71\\ \text{I/O} \ 72 - \text{I/O} \ 77\\ \text{I/O} \ 78 - \text{I/O} \ 83\\ \text{I/O} \ 84 - \text{I/O} \ 89\\ \text{I/O} \ 90 - \text{I/O} \ 95\\ \end{array}$	21, 27, 34, 40, 52, 58, 66, 72, 91, 98, 104, 117, 123, 2, 8,	22, 28, 35, 41, 53, 59, 67, 73, 86, 92, 99, 105, 118, 124, 3, 9,	23, 29, 36, 42, 54, 68, 74, 87, 93, 106, 119, 125, 4, 10,	24, 30, 37, 43, 55, 61, 69, 75, 88, 94, 107, 120, 126, 5, 11,	25, 31, 38, 44, 56, 62, 70, 76, 89, 95, 102, 102, 102, 121, 127, 6, 12,	26 32 39 45 57 63 71 77 90 96 103 109 122 128 7 13	Input/Output Pins - These are the general purpose I/O pins used by the logic array.
GOE 0, GOE 1	64,	114					Global Output Enables input pins.
IN 2, IN 4, IN 5	51,	84,	110				Dedicated input pins to the device.
ispEN	18						Input - Dedicated in-system programming enable input pin. This pin is brought low to enable the programming mode. The MODE, SDI, SDO and SCLK options become active.
SDI/IN 0 ²	20						Input - This pin performs two functions. When ispEN is logic low, it functions as an input pin to load programming data into the device. SDI/INO also is used as one of the two control pins for the isp state machine. When ispEN is high, it functions as a dedicated input pin.
MODE/IN 1 ²	46						Input - This pin performs two functions. When ispEN is logic low, it functions as a pin to control the operation of the isp state machine. When ispEN is high, it functions as a dedicated input pin.
SDO	50						Output - When ispEN is logic low, it functions as an output pin to read serial shift register data.
SCLK/IN 3 ²	78			~	50		Input - This pin performs two functions. When ispEN is logic low, it functions as a clock pin for the Serial Shift Register. When ispEN is high, it functions as a dedicated input pin.
RESET	19			7			Active Low (0) Reset pin which resets all of the GLB and I/O registers in the device.
Y0, Y1, Y2	15	83,	80				Dedicated Clock input. This clock input is connected to one of the clock inputs of all the GLBs on the device.
GND	1, 97,	17, 112	33,	49,	65,	81,	Ground (GND)
VCC	16,	48,	82,	113			Vcc
NC ¹	14,	47,	79,	111,	115,	116	No Connect.

1. NC pins are not to be connected to any active signals, VCC or GND.

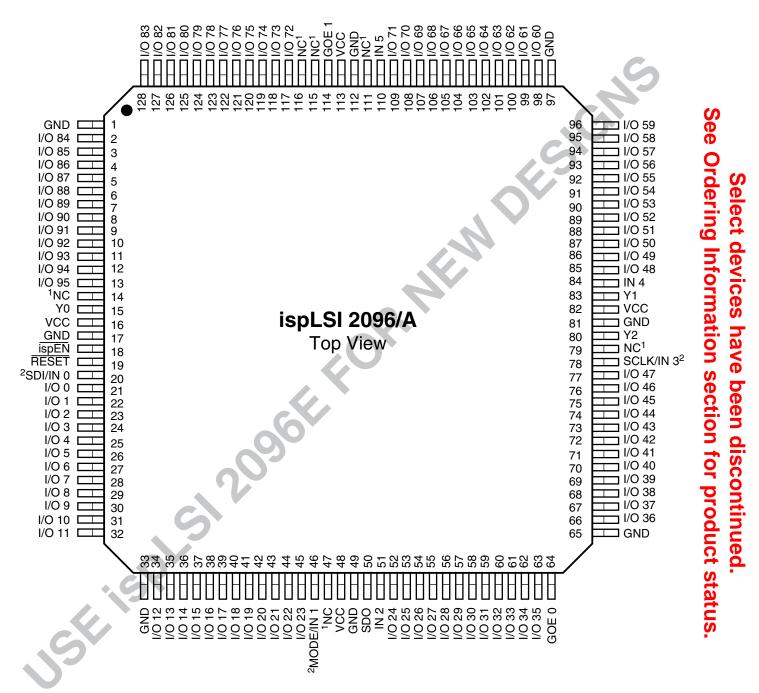
2. Pins have dual function capability.

Table 2-0002-2096



Pin Configuration

ispLSI 2096/A 128-pin PQFP and TQFP Pinout Diagram



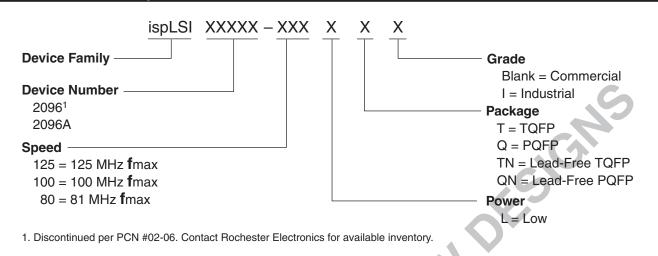
1. NC pins are not to be connected to any active signals, VCC or GND.

2. Pins have dual function capability.

0124A-2096



Part Number Description



ispLSI 2096/A Ordering Information

Conventional Packaging

	COMMERCIAL											
FAMILY	fmax (MHz)	tpd (ns)	ORDERING NUMBER	PACKAGE								
	125	7.5	ispLSI 2096A-125LQ128	128-Pin PQFP								
	125	7.5	ispLSI 2096A-125LT128	128-Pin TQFP								
	100	10	ispLSI 2096A-100LQ128	128-Pin PQFP								
	100	10	ispLSI 2096A-100LT128	128-Pin TQFP								
	81	15	ispLSI 2096A-80LQ128	128-Pin PQFP								
ispLSI	81	15	ispLSI 2096A-80LT128	128-Pin TQFP								
ISPEO	125	7.5	ispLSI 2096-125LQ ¹	128-Pin PQFP								
	125	7.5	ispLSI 2096-125LT ¹	128-Pin TQFP								
	100	10	ispLSI 2096-100LQ ¹	128-Pin PQFP								
	100	10	ispLSI 2096-100LT ¹	128-Pin TQFP								
	81	15	ispLSI 2096-80LQ ¹	128-Pin PQFP								
	81	15	ispLSI 2096-80LT ¹	128-Pin TQFP								

1. Discontinued per PCN #02-06. Contact Rochester Electronics for available inventory.

			INDUSTRIAL	
FAMILY	fmax (MHz)	tpd (ns)	ORDERING NUMBER	PACKAGE
	81	15	ispLSI 2096A-80LQ128I	128-Pin PQFP
ispLSI	81	15	ispLSI 2096A-80LT128I	128-Pin TQFP
	81	15	ispLSI 2096-80LQI ¹	128-Pin PQFP
	81	15	ispLSI 2096-80LTI ¹	128-Pin TQFP

1. Discontinued per PCN #02-06. Contact Rochester Electronics for available inventory.

See Ordering Information section for product status Select devices have been discontinued





ispLSI 2096/A Ordering Information (Cont.)

Lead-Free Packaging

COMMERCIAL					
FAMILY	fmax (MHz)	t pd (ns)	ORDERING NUMBER	PACKAGE	
ispLSI	125	7.5	ispLSI 2096A-125LQN128	Lead-Free 128-Pin PQFP	
	125	7.5	ispLSI 2096A-125LTN128	Lead-Free 128-Pin TQFP	
	100	10	ispLSI 2096A-100LQN128	Lead-Free 128-Pin PQFP	
	100	10	ispLSI 2096A-100LTN128	Lead-Free 128-Pin TQFP	
	81	15	ispLSI 2096A-80LQN128	Lead-Free 128-Pin PQFP	
	81	15	ispLSI 2096A-80LTN128	Lead-Free 128-Pin TQFP	

INDUSTRIAL

FAMILY	fmax (MHz)	t pd (ns)		PACKAGE
ispLSI	81	15	ispLSI 2096A-80LQN128I	Lead-Free 128-Pin PQFP
	81	15	ispLSI 2096A-80LTN128I	Lead-Free 128-Pin TQFP

Revision History

Date	Version	Change Summary				
—	08	Previous Lattice release.				
August 2006	09	Updated for lead-free package options.				

See Ordering Information section for product status. Select devices have been discontinued.